Notice of References Cited					Application/Control No. 10/568,045		Applicant(s)/Patent Under Reexamination HAMASAKA ET AL.	
				Exam	Examiner			
				DANII	DANIEL TEKLE		Page 1 of 1	
U.S. PATENT DOCUMENTS								
*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name			Classification	
*	Α	US-6,580,870	06-2003	Kanazawa et al.			386/240	
	В	US-						
	С	US-						
	D	US-						
	Е	US-						
	F	US-						
	G	US-						
	Н	US-						
	ı	US-						
	J	US-						
	К	US-						
	L	US-						
	М	US-						
FOREIGN PATENT DOCUMENTS								
*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country		Name	Classification	
	N							
	0							
	Р							
	Q							
	R							
	s							
	Т							
NON-PATENT DOCUMENTS								
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)						
	U							

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

٧

W

Χ